This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1	Claim 1 (currently amended): An electrical test probe tip for use with a		
2	probing head, comprising:		
3	(a) a conductive flexible coil having a first end and a second end;		
4	(b) said first end for coupling with a device to be probed;		
5	(c) a connector attached to said second end of said conductive flexible		
6	coil with minimal overlap between said connector and said second		
7	end of said flexible coil; and		
8	(d) said connector for connecting to said probing head; and		
9	(e) said conductive flexible coil at least partially extending beyond said		
10	probing head when said connector is connected to said probing		
11	head.		
12			
1	Claim 2 (previously presented): The electrical test probe tip of claim 1,		
2	said connector being a connecting pin coupleable to said probing head.		
3			
1	Claim 3 (previously presented): The electrical test probe tip of claim 1,		
2	said connector being a square pin coupleable to said probing head.		
3			
1	Claim 4 (withdrawn): The electrical test probe tip of claim 1, said		
2	connector being in integral connection with said probing head.		

Claim 5 (original): The electrical test probe tip of claim 1, said flexible coil having a longitudinal axis and a first diameter, said first diameter being substantially equal throughout said longitudinal axis of said flexible coil.

p. 7

 Claim 6 (withdrawn): The electrical test probe tip of claim 5, said first end having a second diameter larger than said first diameter.

Claim 7 (withdrawn): The electrical test probe tip of claim 1, said first end further comprising a hook.

Claim 8 (withdrawn): The electrical test probe tip of claim 1, said first end further comprising a foot.

 Claim 9 (withdrawn): The electrical test probe tip of claim 1 further comprising an exterior conductive sheath at least partially surrounding said conductive flexible coil.

Claim 10 (withdrawn): The electrical test probe tip of claim 1 further comprising an exterior insulating sheath at least partially surrounding said conductive flexible coil.

Claim 11 (withdrawn): The electrical test probe tip of claim 1 further comprising a conductor disposed at least partially through the axial center of said conductive flexible coil.

Page 3

4

Claim 12 (withdrawn): The electrical test probe tip of claim 11, wherein said conductor is made of a conductive elastomer.

3

1

2

3

9

2

Claim 13 (currently amended): A multipurpose electrical test probe tip interconnectable with a probing head, comprising:

- (a) a conductive flexible member and having a longitudinal length;
- 4 (b) said flexible member having a first end at a first end of said
 5 Iongitudinal length and a second end at a second end of said
 6 Iongitudinal length;
- 7 (c) said flexible member being substantially hollow at said first end; 8 and
 - (d) <u>a connector;</u>
- 10 (e) said connector being connected to said second end of said flexible
 11 member;
- 12 said flexible member being flexible along substantially the entire
 13 longitudinal length of said flexible member when interconnected
 14 with said connector, first end-of-said conductive flexible member for
 15 securely flexibly coupling with a component to be probed-so as to
 16 allow movement of said probing head.

17

1

2

3

Claim 14 (previously presented): The multipurpose electrical test probe tip of claim 13, wherein said second end of said conductive flexible member is interconnectable with said probing head.

4

4

Application No. 10/020,707 Amendment dated February 25, 2004 Reply to Office action of January 16, 2004

Claim 15 (withdrawn): The multipurpose electrical test probe tip of claim 1 14, wherein said second end of said conductive flexible member is integral with said 2 3 probing head. 4 Claim 16 (original): The multipurpose electrical test probe tip of claim 14, 1 said second end of said conductive flexible member further comprising a connector 2 3 coupleable with said probing head. 4 Claim 17 (original): The multipurpose electrical test probe tip of claim 13, 1 2 said flexible member having a longitudinal axis and a first diameter, said first diameter 3 being substantially equal throughout said longitudinal axis of said flexible coil. 4 Claim 18 (withdrawn): The multipurpose electrical test probe tip of claim 1 2 17, said first end having a second diameter larger than said first diameter. 3 Claim 19 (withdrawn): The multipurpose electrical test probe tip of claim 1 13, said first end further comprising a hook. 2 3 Claim 20 (withdrawn): The multipurpose electrical test probe tip of claim 1 2 13, said first end further comprising a foot. 3 Claim 21 (withdrawn): The multipurpose electrical test probe tip of claim 1 13 elaim 1 further comprising an exterior conductive sheath at least partially surrounding 2 said conductive flexible member. 3

1 Claim 22 (withdrawn): The multipurpose electrical test probe tip of claim 13 claim-1 further comprising an exterior insulating sheath at least partially surrounding 2 said conductive flexible member. 3 4 Claim 23 (withdrawn): The multipurpose electrical test probe tip of claim 1 2 13 claim 1 further comprising a conductor disposed at least partially through the axial 3 center of said conductive flexible member. 4 Claim 24 (withdrawn): A method for using a multipurpose electrical test 1 2 probe having a probing head, said method comprising the steps of: 3 (a) providing a flexible spring tip, said flexible spring tip having a connector end connectable to said probing head and a flexible coil 4 contact end remote from said probing head; 5 connecting said connector end to said probing head; and 6 (b) 7 (c) placing said contact end in flexible electrical contact with an electrical component to be probed so as to permit movement of 8 said probing head. 10 Claim 25 (cancelled): 1 2 Claim 26 (cancelled): 1 2 Claim 27 (cancelled): 1 2

1 Claim 28 (previously presented): The electrical test probe tip of claim 1. 2 said conductive flexible coil being substantially hollow at said first end. 3 1 Claim 29 (previously presented): The electrical test probe tip of claim 1, 2 said conductive flexible coil being substantially hollow. 3 1 Claim 30 (previously presented): The electrical test probe tip of claim 1. 2 said first end of said conductive flexible coil being suitable to receive a device to be 3 probed therein. 4 1 Claim 31 (previously presented): The electrical test probe tip of claim 1, 2 wherein said first end of said conductive flexible coil at least partially surrounds a device 3 to be probed. 4 1 Claim 32 (previously presented): The multipurpose electrical test probe tip 2 of claim 13, said conductive flexible member being substantially hollow. 3 1 Claim 33 (previously presented): The multipurpose electrical test probe tip 2 of claim 13, said first end of said conductive flexible member being suitable to receive a 3 component to be probed therein. 4 1 Claim 34 (previously presented): The multipurpose electrical test probe tip 2 of claim 13, wherein said first end of said conductive flexible member at least partially 3 surrounds a component to be probed. 4

1	Clai	m 35 (withdrawn): The electrical test probe tip of claim 1, said first	
2	end of said flexible coil having at least one additional coupling mechanism extending		
3	therefrom, said additional coupling mechanism selected from the group consisting of:		
4	(a)	an enlarged coil having a diameter larger than the diameter of said	
5		flexible coil;	
6	(b)	a hook; and	
7	(c)	a foot.	
8		•	
1	Clai	m 36 (withdrawn): The electrical test probe tip of claim 13, said first	
2	end of said flexible	e coil having at least one additional coupling mechanism extending	
3	therefrom, said additional coupling mechanism selected from the group consisting of:		
4	(a)	an enlarged coil having a diameter larger than the diameter of said	
5		flexible coil;	
6	(b)	a hook; and	
7	(c)	a foot.	
8			
1	Clair	m 37 (cancelled):	
2		·	
1	Clair	m 38 (cancelled):	
2			
1	Clair	m 39 (new): An electrical test probe tip, comprising:	
2	(a)	a conductive flexible coil having a first end and a second end, said	
3		first end opposite said second end;	
4	(b)	a connector;	

Page 8

14

Application No. 10/020,707 Amendment dated February 25, 2004 Reply to Office action of January 7, 2004

6	(c)	device to be probed; and	
7 8	(d)	said connector attached to the extreme second end of said conductive flexible coil with substantially no overlap between said	
9		conductive flexible coil and said connector.	
10			
1	Clain	n 40 (new): The electrical test probe tip of claim 39, said conductive	
2	flexible coil having	a longitudinal length, said conductive flexible coil being flexible along	
3	substantially said entire longitudinal length of said conductive flexible coil when		
4	interconnected with said connector.		
5			
1	Clain	n 41 (new): A multipurpose electrical test probe tip interconnectable	
2	with a probing head, comprising:		
3	(a)	a conductive flexible member and having a longitudinal length;	
4	(d)	a connector;	
5	(b)	said flexible member having a first end at a first end of said	
6		longitudinal length and a second end at a second end of said	
7		longitudinal length;	
8	(c)	said flexible member being substantially hollow at said first end;	
9	(e)	said connector being connected to said second end of said flexible	
10		member;	
11	(f)	said flexible member being flexible along substantially the entire	
12		longitudinal length of said flexible member when interconnected	
13		with said connector.	

Claim 42 (new): The multipurpose electrical test probe tip of claim 41, said connector attached to said second end of said conductive flexible member with minimal overlap between said connector and said second end of said conductive flexible member.

5

2

3

1

2

3

4

Claim 43 (new): The multipurpose electrical test probe tip of claim 41, said connector attached to the extreme end of said second end of said conductive flexible member.

4